

1. Global joint venture starts operations as WeEn Semiconductors

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WeEn Semiconductors



Product data sheet

1. General description

Planar passivated four quadrant triac in a SOT428 (DPAK) surface-mountable plastic package intended for use in bidirectional switching and phase control applications.

2. Features and benefits

- High blocking voltage capability
- Less sensitive gate for improved noise immunity
- Planar passivated for voltage ruggedness and reliability
- Surface-mountable package
- Triggering in all four quadrants

3. Applications

- General purpose motor control
- General purpose switching

4. Quick reference data

Table 1. Quick reference data

| Symbol | Parameter | Conditions | Mi | п Тур | Max | Unit |
|---------------------|--|--|----|-------|-----|------|
| V_{DRM} | repetitive peak off- state voltage | | - | - | 600 | V |
| I _{TSM} | non-repetitive peak on- state current | full sine wave; $T_{j(init)} = 25 \text{ °C}$; $t_p = 20 \text{ ms}$; Fig. 4; Fig. 5 | - | - | 65 | A |
| I _{T(RMS)} | RMS on-state current | full sine wave; $T_{mb} \le 102 ^{\circ}\text{C}$; Fig. 1; Fig. 2; Fig. 3 | - | - | 8 | A |
| Static char | acteristics | | | | | |
| I _{GT} | gate trigger current | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ G+;$ $T_j = 25 \text{ °C}; Fig. 7$ | - | 5 | 35 | mA |
| | | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ G-;$ $T_j = 25 \text{ °C}; Fig. 7$ | - | 8 | 35 | mA |
| | | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; \text{ T2- G-};$ $T_j = 25 \text{ °C}; \underline{\text{Fig. 7}}$ | - | 11 | 35 | mA |
| | | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2- G+;$ $T_j = 25 \text{ °C}; Fig. 7$ | - | 30 | 70 | mA |





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5. Pinning information

Table 2. Pinning information

| Pin | Symbol | Description | Simplified outline | Graphic symbol |
|-----|--------|--------------------------------|--------------------|----------------|
| 1 | T1 | main terminal 1 | mb | T2——T1 |
| 2 | T2 | main terminal 2 | | Sym051 |
| 3 | G | gate | | · |
| mb | T2 | mounting base; main terminal 2 | 1 3 | |
| | | | DPAK (SOT428) | |

6. Ordering information

Table 3. Ordering information

| Type number | Package | | | | |
|-------------|---------|---|---------|--|--|
| | Name | Description | Version | | |
| BT137S-600 | DPAK | plastic single-ended surface-mounted package (DPAK); 3 leads (one lead cropped) | SOT428 | | |

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7. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol | Parameter | Conditions | Min | Max | Unit |
|---------------------|--------------------------------------|---|-----|-----|------------------|
| V_{DRM} | repetitive peak off-state voltage | | - | 600 | V |
| I _{T(RMS)} | RMS on-state current | full sine wave; $T_{mb} \le 102 \text{ °C}$; Fig. 1; Fig. 2; Fig. 3 | - | 8 | Α |
| I _{TSM} | non-repetitive peak on-state current | full sine wave; $T_{j(init)} = 25 \text{ °C}$; $t_p = 20 \text{ ms}$; Fig. 4; Fig. 5 | - | 65 | Α |
| | | full sine wave; $T_{j(init)} = 25 \text{ °C}$; $t_p = 16.7 \text{ ms}$ | - | 71 | Α |
| I ² t | I ² t for fusing | t _p = 10 ms; SIN | - | 21 | A ² s |
| dl _T /dt | rate of rise of on-state current | I_T = 12 A; I_G = 0.2 A; dI_G/dt = 0.2 A/ μ s; T2+ G+ | - | 50 | A/µs |
| | | I_T = 12 A; I_G = 0.2 A; dI_G/dt = 0.2 A/ μ s; T2+ G- | - | 50 | A/µs |
| | | I_T = 12 A; I_G = 0.2 A; dI_G/dt = 0.2 A/ μ s; T2- G- | - | 50 | A/µs |
| | | I_T = 12 A; I_G = 0.2 A; dI_G/dt = 0.2 A/ μ s; T2- G+ | - | 10 | A/µs |
| I _{GM} | peak gate current | | - | 2 | Α |
| P _{GM} | peak gate power | | - | 5 | W |
| P _{G(AV)} | average gate power | over any 20 ms period | - | 0.5 | W |
| T _{stg} | storage temperature | | -40 | 150 | °C |
| Tj | junction temperature | | - | 125 | °C |

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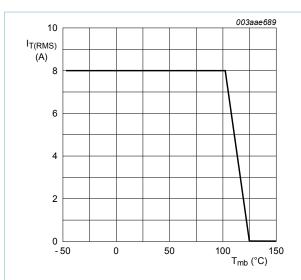


Fig. 1. RMS on-state current as a function of mounting base temperature; maximum values

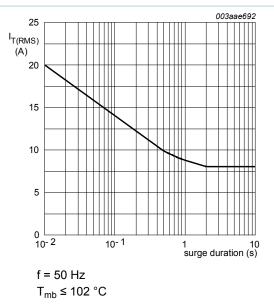
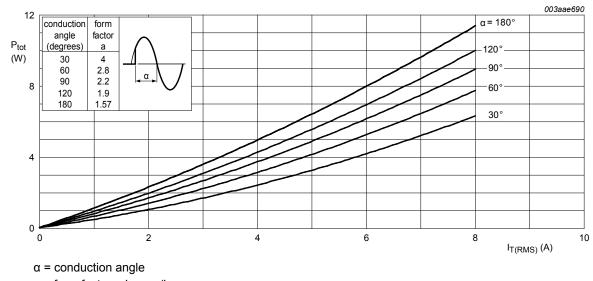


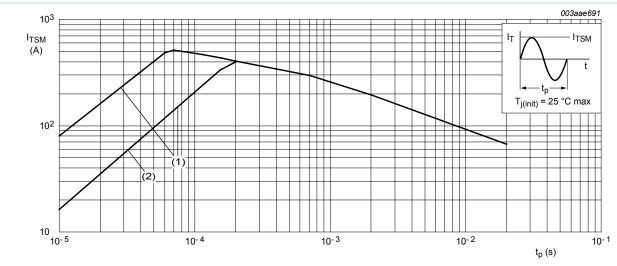
Fig. 2. RMS on-state current as a function of surge duration; maximum values



a = form factor = $I_{T(RMS)}/I_{T(AV)}$

Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values

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 $t_p \le 20 \text{ ms}$

- (1) dI_T/dt limit
- (2) T2- G+ quadrant limit

Fig. 4. Non-repetitive peak on-state current as a function of pulse width; maximum values

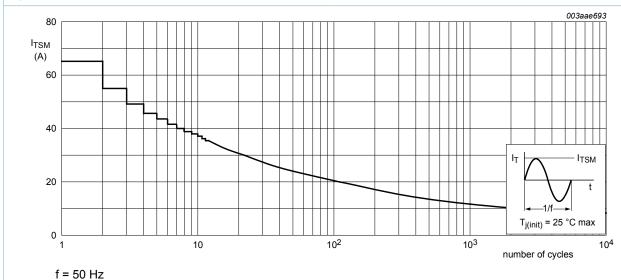


Fig. 5. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values

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8. Thermal characteristics

Table 5. Thermal characteristics

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|-----------------------|---|--------------------------------------|-----|-----|-----|------|
| R _{th(j-mb)} | thermal resistance from junction to mounting base | half cycle; Fig. 6 | - | - | 2.4 | K/W |
| | | full cycle; Fig. 6 | - | - | 2 | K/W |
| R _{th(j-a)} | thermal resistance from junction to ambient | PCB (FR4) mounted; minimum pad sizes | - | 75 | - | K/W |

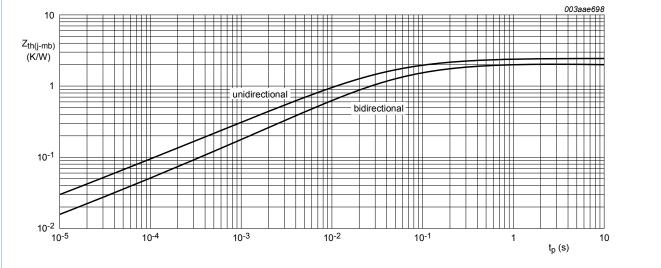


Fig. 6. Transient thermal impedance from junction to mounting base as a function of pulse width

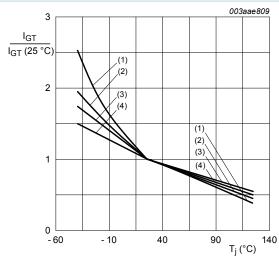
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9. Characteristics

Table 6. Characteristics

| Table 6. Symbol | Characteristics Parameter | Conditions | Min | Тур | Max | Unit |
|-----------------------|---------------------------------------|--|------|-----|------|------|
| Static cha | aracteristics | | | | | |
| I _{GT} | gate trigger current | V _D = 12 V; I _T = 0.1 A; T2+ G+; T _j = 25 °C; <u>Fig. 7</u> | - | 5 | 35 | mA |
| | | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2+ \text{ G-};$ $T_j = 25 ^{\circ}\text{C}; \underline{\text{Fig. 7}}$ | - | 8 | 35 | mA |
| | | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2- \text{G-};$ $T_j = 25 \text{ °C}; Fig. 7$ | - | 11 | 35 | mA |
| | | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T2- G+;$ $T_j = 25 \text{ °C}; Fig. 7$ | - | 30 | 70 | mA |
| IL | latching current | V _D = 12 V; I _G = 0.1 A; T2+ G+; T _j = 25 °C; <u>Fig. 8</u> | - | 7 | 30 | mA |
| | | $V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T2+ G-;$ $T_j = 25 \text{ °C}; Fig. 8$ | - | 16 | 45 | mA |
| | | $V_D = 12 \text{ V; } I_G = 0.1 \text{ A; T2- G-;}$ $T_j = 25 \text{ °C; } Fig. 8$ | - | 5 | 30 | mA |
| | | $V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; \text{ T2- G+};$ $T_j = 25 ^{\circ}\text{C}; \underline{\text{Fig. 8}}$ | - | 7 | 45 | mA |
| I _H | holding current | V _D = 12 V; T _j = 25 °C; <u>Fig. 9</u> | - | 5 | 20 | mA |
| V _T | on-state voltage | I _T = 10 A; T _j = 25 °C; <u>Fig. 10</u> | - | 1.3 | 1.65 | V |
| V_{GT} | gate trigger voltage | $V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 \text{ °C};$ Fig. 11 | - | 0.7 | 1 | V |
| | | V _D = 400 V; I _T = 0.1 A; T _j = 125 °C; Fig. 11 | 0.25 | 0.4 | - | V |
| I _D | off-state current | V _D = 600 V; T _j = 125 °C | - | 0.1 | 0.5 | mA |
| Dynamic | characteristics | | , | | | |
| dV _D /dt | rate of rise of off-state voltage | V_{DM} = 402 V; T_j = 125 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit | 100 | 250 | - | V/µs |
| dV _{com} /dt | rate of change of commutating voltage | V_D = 400 V; T_j = 95 °C; dI_{com}/dt = 3.6 A/ ms; I_T = 8 A; gate open circuit | - | 20 | - | V/µs |
| t _{gt} | gate-controlled turn-on time | I_{TM} = 12 A; V_D = 600 V; I_G = 0.1 A; $dI_G/$ dt = 5 A/ μ s | - | 2 | - | μs |

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- (1) T2- G+
- (2) T2- G-
- (3) T2+ G-
- (4) T2+ G+

Fig. 7. Normalized gate trigger current as a function of junction temperature

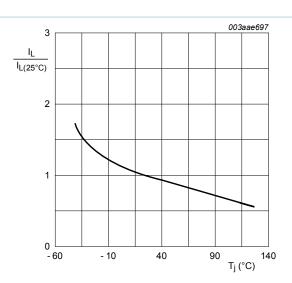


Fig. 8. Normalized latching current as a function of junction temperature

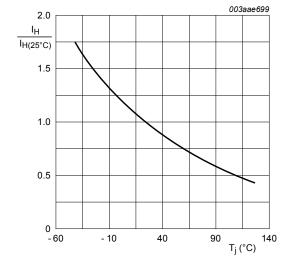
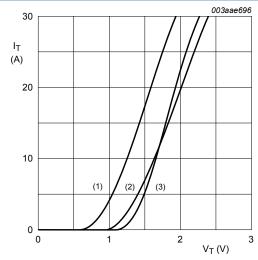


Fig. 9. Normalized holding current as a function of junction temperature



 $V_0 = 1.264 \text{ V}$

 $R_s = 0.038 \Omega$

(1) T_i = 125 °C; typical values

(2) T_i = 125 °C; maximum values

(3) $T_j = 25$ °C; maximum values

Fig. 10. On-state current as a function of on-state voltage

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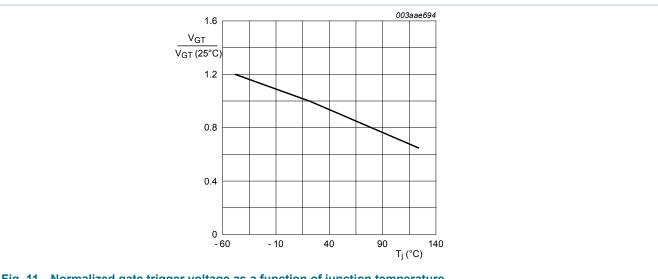
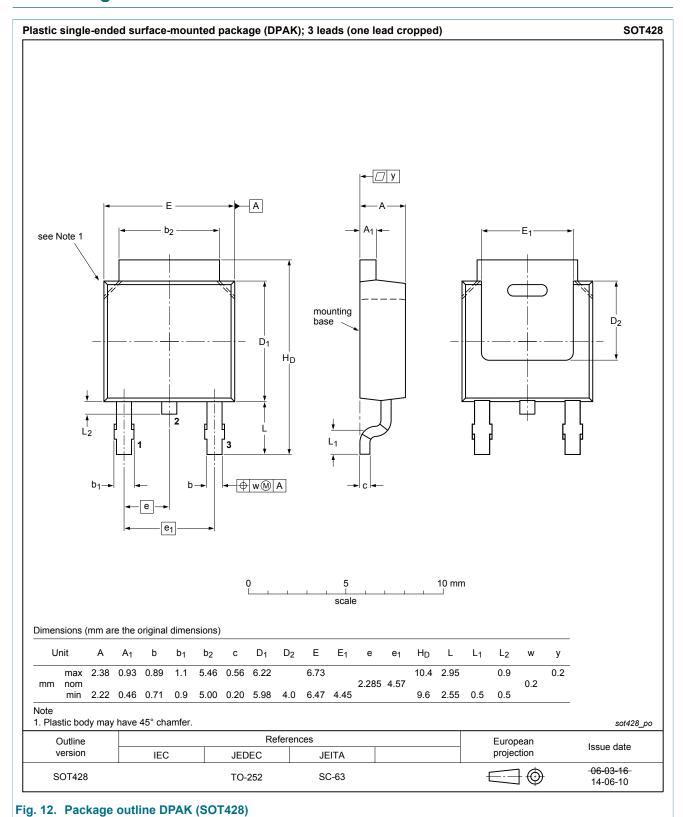


Fig. 11. Normalized gate trigger voltage as a function of junction temperature

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10. Package outline



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11. Legal information

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|--------------------------------------|--------------------|---|
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